



ARMI

ISO Certified · 9001 · 17025 · 17043 · 17034

Certificate of Analysis

IARM Fe4820-18

Low Alloy Steel AISI 4820 / UNS G48200

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	0.022 ± 0.001	As	0.006 ± 0.003	C	0.192 ± 0.006	Co	0.0107 ± 0.0007
Cr	0.144 ± 0.002	Cu	0.167 ± 0.003	Mn	0.541 ± 0.009	Mo	0.287 ± 0.007
N	0.007 ± 0.001	Nb	0.002 ± 0.001	Ni	3.51 ± 0.03	O	0.003 ± 0.002
P	0.011 ± 0.004	S	0.018 ± 0.001	Si	0.26 ± 0.01	Sn	0.0089 ± 0.0005
Ti	0.0011 ± 0.0008	V	0.0015 ± 0.0005	W	0.004 ± 0.002		

Indicative Values listed in ppm

B (3)	Ca (<50)	Cd (<10)	H (<1)	Hf (<10)	Mg (<10)	Pb (<60)
Pd (<10)	Sb (18)	Se (<50)	Ta (<50)	Y (<10)	Zn (<10)	Zr (10)

Description and Intended Use

This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** certified laboratories. This CRM may come in the form of a solid disk, chips, or powder. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Instructions for Use

1. The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface.
2. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams.
3. The material should be stored in a cool, dry location when not in use.
4. Chips are not recommended for gas analysis.

The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	B	C	Ca	Cd	Co	Cr	Cu	H	Hf	Mg	Mn	Mo	N	Nb
1	0.0193	0.00337	0.0001	0.171	0.00015	0.0005	0.009	0.1398	0.1558	<0.0001	<0.001	0.00009	0.5152	0.273	0.0035	0.00006
2	0.02	0.004	0.00018	0.185	<0.005	<0.001	0.01	0.14	0.16			<0.001	0.525	0.276	0.0042	0.0011
3	0.0204	0.0045	0.0002	0.187			0.0102	0.14	0.166				0.526	0.281	0.007	0.0015
4	0.02043	0.0058	0.00027	0.188			0.0105	0.1417	0.1667				0.533	0.2835	0.007	0.0015
5	0.0205	0.006	0.0009	0.19			0.01078	0.143	0.167				0.536	0.284	0.0077	0.002
6	0.021	0.0074	<0.0005	0.19			0.011	0.144	0.168				0.54	0.285	0.00777	0.003
7	0.021	0.008	<0.001	0.191			0.011	0.144	0.1685				0.545	0.286	0.00786	<0.001
8	0.0212	0.0128		0.192			0.012	0.144	0.169				0.545	0.287	0.008	<0.005
9	0.023			0.1938			0.012	0.1445	0.17				0.546	0.287	0.008	
10	0.023			0.2014				0.1446	0.17				0.5487	0.291	0.0094	
11	0.024			0.2055				0.145	0.171				0.55	0.3062		
12	0.0252			0.2073				0.1485	0.173				0.56	0.31		
13								0.1518					0.5657			
14																
15																
Mean	0.022	0.006	0.0003	0.192			0.0107	0.144	0.167				0.541	0.287	0.007	0.002
STDV.	0.002	0.003	0.0003	0.01			0.001	0.003	0.005				0.01	0.01	0.002	0.001
Certified	0.022	0.006	(0.0003)	0.192	(<0.005)	(<0.001)	0.0107	0.144	0.167	(<0.0001)	(<0.001)	(<0.001)	0.541	0.287	0.007	0.002
U _{CRM}	0.001	0.003		0.006			0.0007	0.002	0.003				0.009	0.007	0.001	0.001
Methods	I,O,X,IM	I,O,X,IM	I,O,IM	C,O	O,IM,I	IM	I,O,X,IM	I,O,X,IM	I,O,X,IM	F	IM	IM	I,O,X	I,O,X,IM	F	O,P,X,IM,I

	Ni	O	P	Pb	Pd	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr
1	3.392	0.00088	0.0044	0.00016	<0.001	0.015	0.0011	0.00007	0.2296	0.008	0.005	0.00019	0.00077	0.00079	0.0004	0.00007
2	3.435	0.00089	0.0068	0.00016		0.0162	0.00157	<0.001	0.25	0.0082	<0.001	0.0003	0.00119	0.0013	0.0004	0.0009
3	3.504	0.0012	0.007	0.004		0.017	0.0017	<0.005	0.2513	0.0083	<0.001	0.0009	0.0013	0.0035	<0.001	0.001
4	3.512	0.0013	0.007	0.0055		0.017	0.002		0.253	0.0084		0.00144	0.0017	0.0045		0.002
5	3.514	0.0023	0.00707	<0.001		0.01735	0.0024		0.2555	0.0086		0.0017	0.002	0.005		<0.001
6	3.5167	0.0035	0.0079	<0.001		0.0176			0.26	0.009		0.002	0.002	0.0056		
7	3.5252	0.005	0.0082			0.01797			0.26	0.009				0.007		
8	3.528	0.0055	0.0087			0.0184			0.261	0.00905						
9	3.53		0.009			0.019			0.2623	0.01						
10	3.542		0.011			0.0192			0.264	0.01						
11	3.55		0.0118			0.0197			0.278							
12	3.6019		0.023			0.021			0.2877							
13			0.025						0.303							
14																
15																
Mean	3.51	0.003	0.011	0.002		0.018	0.0018		0.26	0.0089		0.0011	0.0015	0.004		0.0010
STDV.	0.05	0.002	0.006	0.003		0.002	0.0005		0.02	0.0007		0.0007	0.0005	0.002		0.0008
Certified	3.51	0.003	0.011	(<0.006)	(<0.001)	0.018	(0.0018)	(<0.005)	0.26	0.0089	(<0.005)	0.0011	0.0015	0.004	(<0.001)	(0.001)
U _{CRM}	0.03	0.002	0.004			0.001			0.01	0.0005		0.0008	0.0005	0.002		
Methods	I,O,X	F	I,O,X,IM	O,IM	IM	C,O,X	X,IM	X,IM	I,O,X,IM	I,O,X,IM	O,X,IM	I,O,X,IM	I,O,X,IM	I,O,X,IM	X,IM	O,X,IM

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

Certification Laboratories

Davis Alloys Manufacturing, LLC	Sharpsville, PA	Laboratory Testing, Inc.	Hatfield, PA
Exova - Burlington	Burlington, ON	Cronimet Specialty Metals USA, Inc.	Wheatland, PA
Anderson Laboratories, Inc.	Greendale, WI	TimkenSteel Corporation	Canton, OH
Laboratorio Prove Materiali S. Marco srl	Schio, Italy	LGC Standards	Manchester, NH
EAG Laboratories, Inc.	Liverpool, NY	Dirats Laboratories	Westfield, MA
NSL Analytical Services, Inc.	Cleveland, OH		

Certification laboratories have demonstrated performance and traceability by utilizing a variety of test methods all under the scope of ISO 17025. Some of the specific CRMs and SRMs used in the analysis of the material covered by this certificate are:

NIST 1263 NIST 132A NIST 16F NIST 1754 NIST 1761 NIST 1764 NIST 1765 NIST 293 NIST 3136 NIST 361 NIST 362 NIST 363 NIST 364 NIST 368

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}}) \qquad 2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Expiration

The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

David Coler, General Manager

Analytical Reference Materials International

